



5/9/2009

RELIABILITY MONITOR REPORT
FOR

TSMC 0.5 μ m Silicon Gate CMOS

MAXIM Integrated Products

120 San Gabriel Dr.
Sunnyvale, CA 94086

This Report was prepared by
Maxim Reliability Engineering

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

LMX331AUK+	MAX4234AUD+	MAX6902ETA
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The calculated failure rate for devices using this process is:

FAILURE RATE: **MTTF (YRS): 17095** **FITS: 6.7**

The parameters used to calculate this failure rate are as follows:

Cf: 60% **Ea: 0.7** **Tu: 25 °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 1/1/2008 and 12/31/2008.

Process Information:

Process Description: TSMC 0.5µm Silicon Gate CMOS

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	0712	LMX331AUK+	135C	1000 HRS	80	0	K080BA004F#
HIGH TEMP OP LIFE	0735	MAX6902ETA	135C	192 HRS	55	0	K2F0DA025BQ
Total:						0	

STORAGE LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
STORAGE LIFE	0819	MAX4234AUD+	150C	500 HRS	45	0	K9L0BQ001R#
Total:						0	

FAILURE RATE: **MTTF (YRS): 17095** **FITS: 6.7**